

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re the Application of: **Takashi FUJITA et al.**

Art Unit: **1797**

Application Number: **10/561,538**

Examiner: **Xiaoyun Xu**

Filed: **December 19, 2005**

Confirmation Number: **9367**

For: **SPECIFIC COMPONENT MEASURING METHOD BY SPECTRAL  
MEASUREMENT**

Attorney Docket Number: **053362**  
Customer Number: **38834**

**RESPONSE UNDER 37 C.F.R. § 1.116**  
**EXPEDITED PROCESSING REQUESTED**

**Mail Stop: AF**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

June 10, 2010

Sir:

This paper is filed in response to the Office Action dated March 3, 2010.

Remarks begin on page 2 of this paper.